
Thin-Film Design Refinement Via Efficient Parallel Combinatorial Search

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OIC 2016

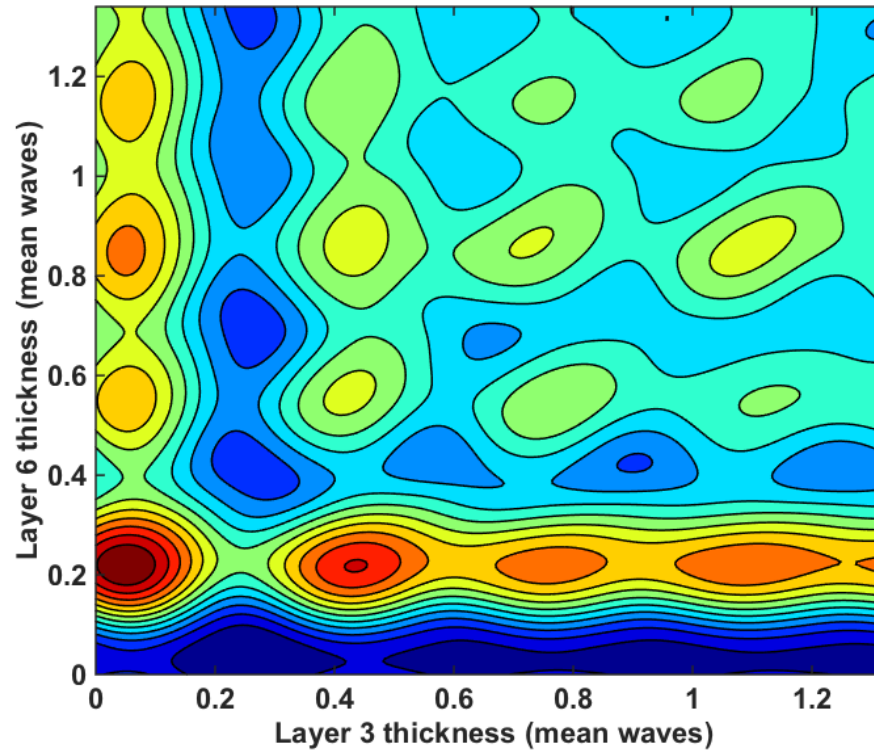




Thin Film Merit Function Structure

- 14 layer AR coating on 1.52 substrate
- Uniform thin layer initial conditions
- low index: 1.35, high index: 2.35

Merit function of AR coating versus two layer thicknesses



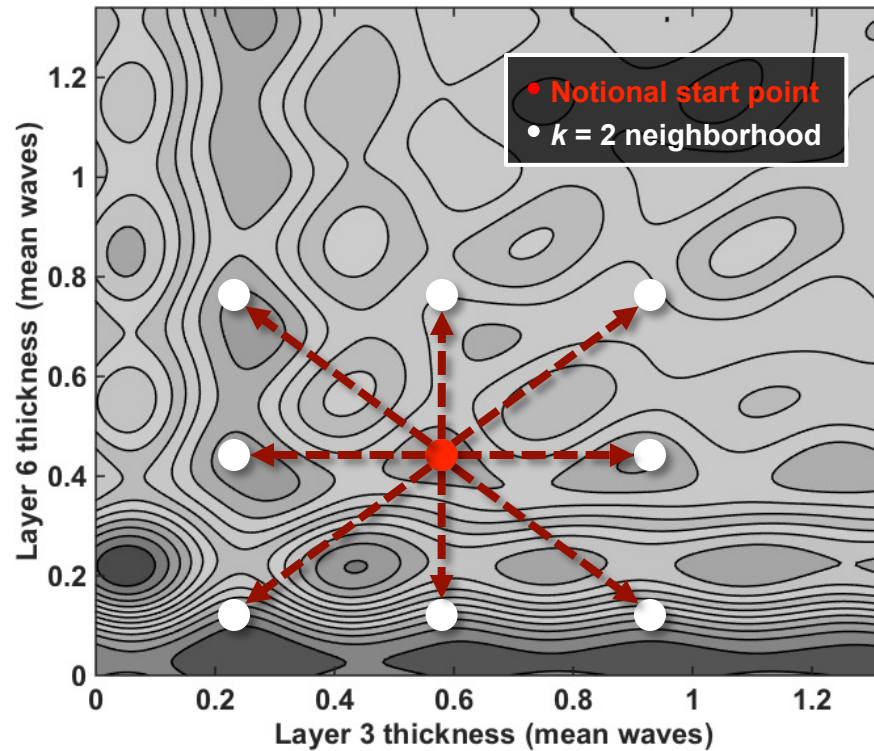
- Local minima tend to be spaced quasi-uniformly by $\frac{1}{4}$ - to $\frac{1}{2}$ -wave of mean optical thickness



Combinatorial Search Concept

- 14 layer AR coating on 1.52 substrate
- Uniform thin layer initial conditions
- low index: 1.35, high index: 2.35

Merit function of AR coating versus two layer thicknesses

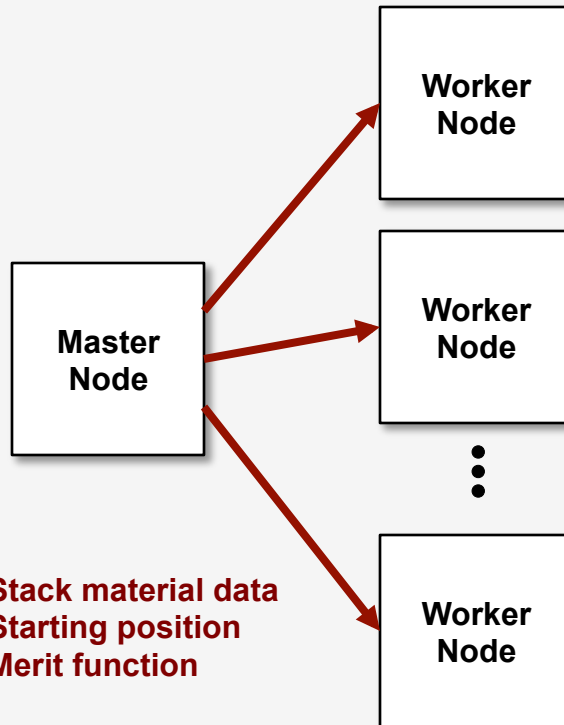


- Searching for better local minima can be done by simultaneously perturbing groups of k layers by enough to escape local minima and reoptimizing



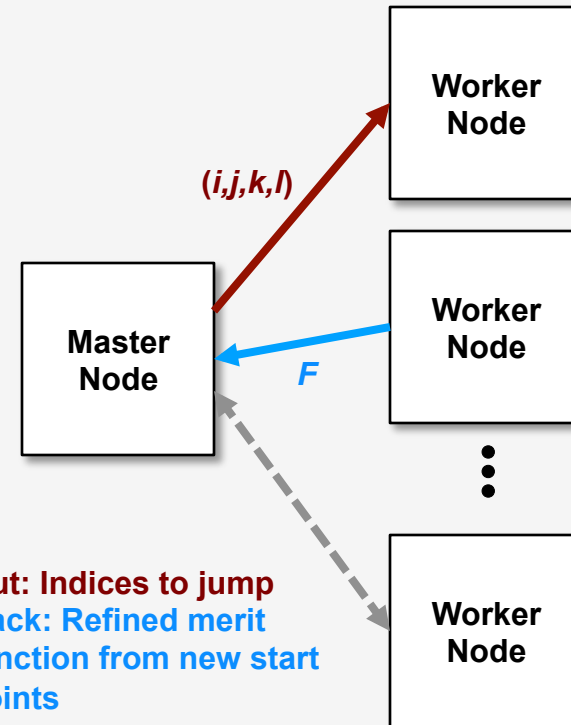
Parallelization Approach

Initialization



- Stack material data
- Starting position
- Merit function

Asynchronous Scheduling

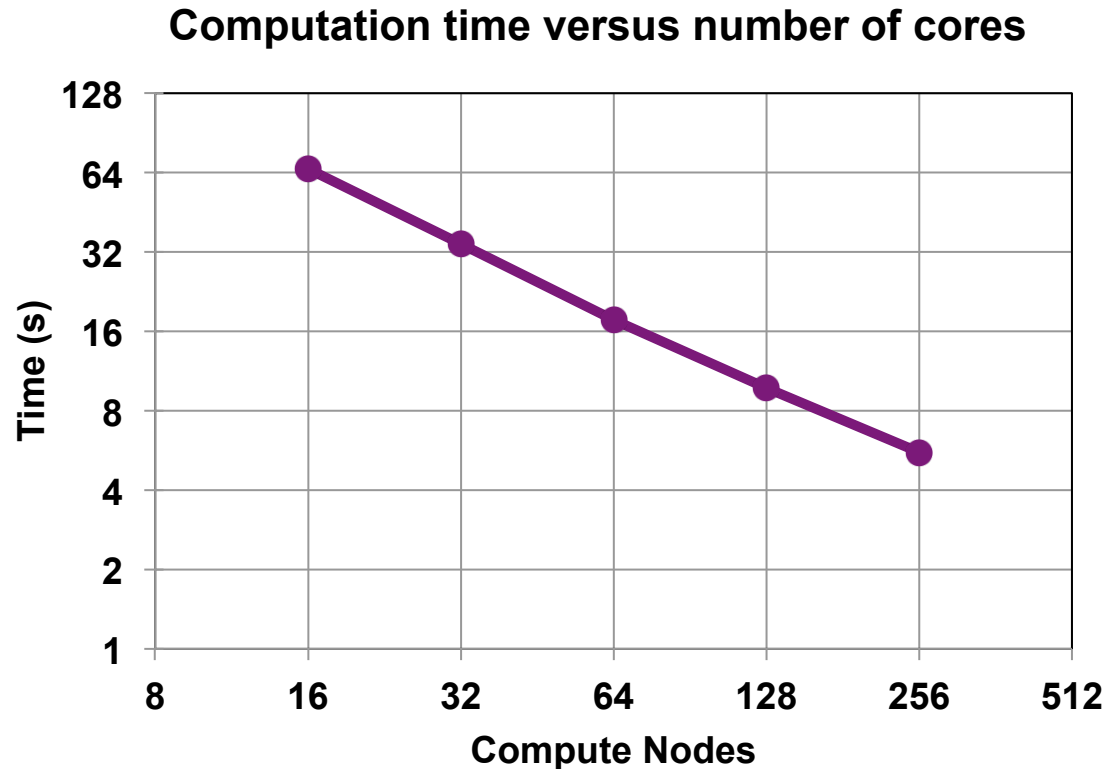


- Out: Indices to jump
- Back: Refined merit function from new start points

- Dynamic computation assignment prioritizes uniform node utilization over communication efficiency in the face of unpredictable computation times



Implementation Efficiency

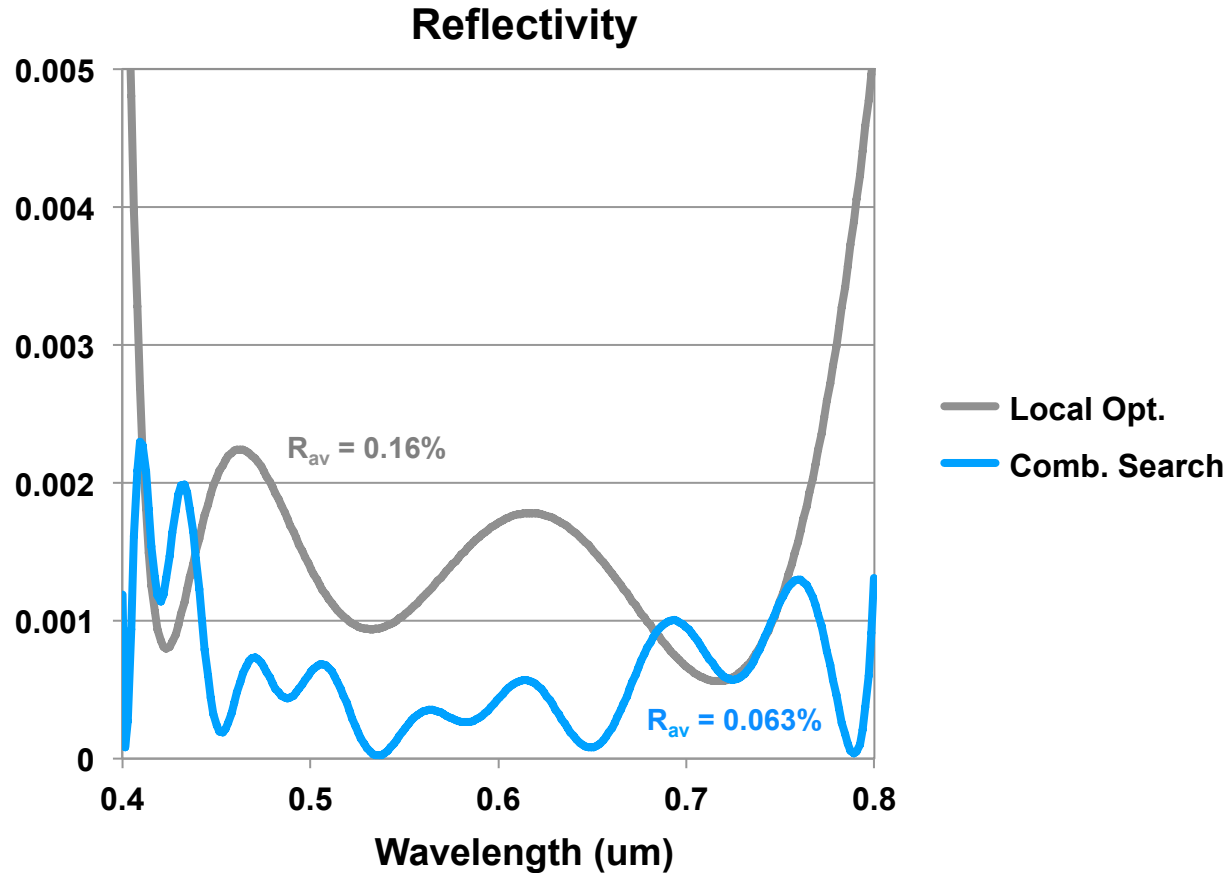


- Computation time scales linearly with processor count
- Parallel algorithm is not communication-limited



AR Coating Design Example

- 18 layer AR coating on 1.52 substrate
- Low index: 1.38, high index: 2.35
- Trivial start point: uniform $1/20^{\text{th}}$ mean wave layers
- $k = 2$

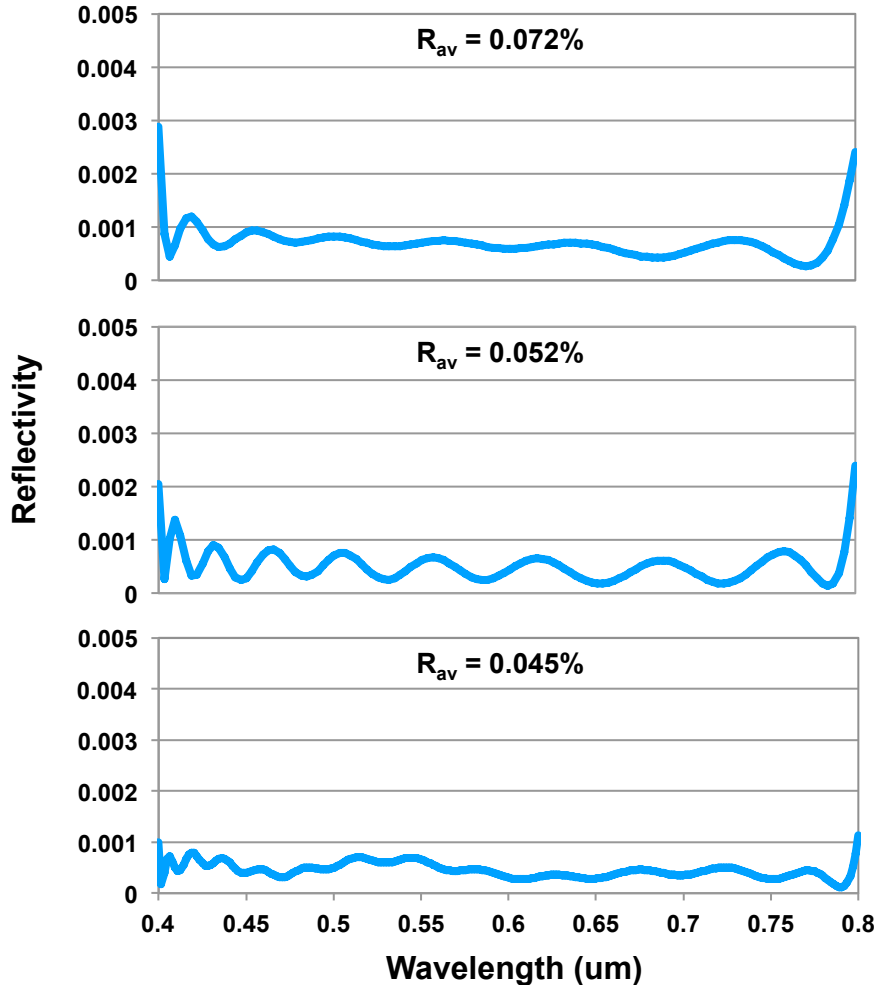




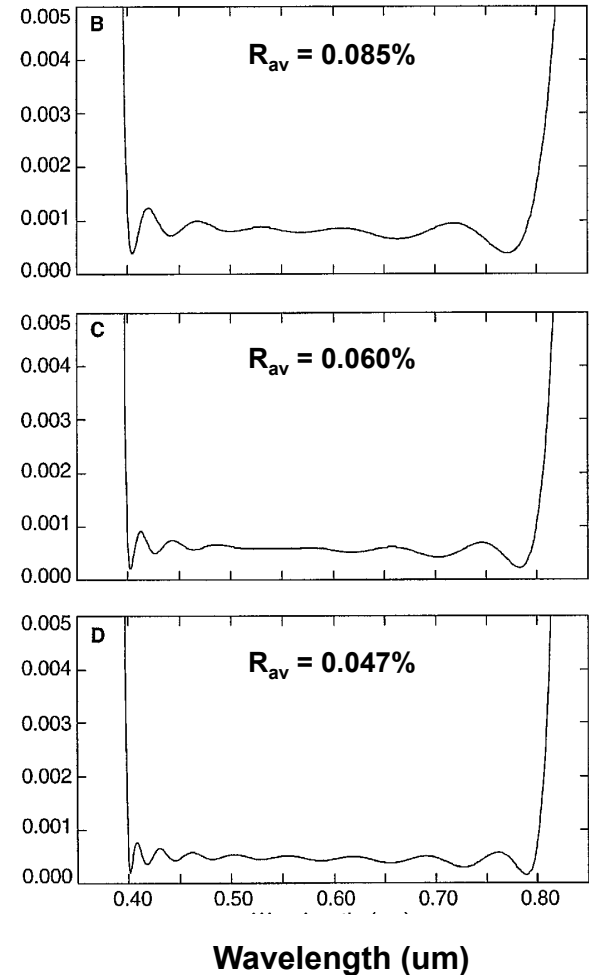
AR Coating Design Results

• 14 layer AR coating on 1.52 substrate • Low index: 1.38, high index: 2.35 • $k = 4$ search space

Combinatorial opt. from trivial start point



Antireflection coating literature*





Future Work

- **Test on other design genres**
 - Initial work on stop/pass-band shows promise, albeit not as dramatic as AR coating
- **Integrate into larger optimization schemes (e.g. gradual refinement, needle optimization, etc.)**
- **Adaptive jump size determination**
- **Implement on commodity cloud hardware (e.g. Amazon EC2)**
- **Integrate with manufacturing tolerance merit functions**